# **TDK·Lambda**

# **RTHB-5080**

# **RELIABILITY DATA**

DWG. No.SC575-RTHB-80-001					
QA	R&D				
APPROVED BY	APPROVED BY	CHECKED BY	DRAWN BY		
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#### **RTHB-5080**

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The following data are typical values. As all units have nearly the same characteristics, the data to be considered as ability values.

#### **RTHB-5080**

1. Calculated values of MTBF

MODEL : RTHB-5080

(1) Calculating Method

Calculated based on parts stress reliability projection of MIL-HDBK-217F NOTICE2.

Individual failure rates  $\lambda$  G is given to each part and MTBF is calculated by the count of each part.

$$MTBF = \frac{1}{\lambda_{equip}} = \frac{1}{\sum_{i=1}^{n} N_i (\lambda_G \pi_Q)_i} \times 10^6 \text{ (hours)}$$

λ equip	: Total equipment failure rate (Failure / 10 <sup>6</sup> Hours)
λG	: Generic failure rate for the <i>i</i> th generic part
	(Failure/ 10 <sup>6</sup> Hours)
Ni	: Quantity of <i>i</i> th generic part
Ν	: Number of different generic part categories
πQ	: Generic quality factor for the <i>i</i> th generic part ( $\pi Q = 1$ )

- (2) MTBF Values
  - GF : Ground, Fixed

MTBF = 1,906,069 (Hours)

#### **RTHB-5080**

2. Vibration Test

### MODEL : RTHB-5080 (Representation Product : RTHN-5150)

- (1) Vibration Test Class Frequency Variable Endurance Test
- (2) Equipment Used Controller VS-1000-6, Vibrator 905-FN ( IMV CORP.)
- (3) The Number of D.U.T. (Device Under Test) 2 units
- (4) Test Condition
  - Frequency : 10~55Hz
  - · Amplitude : 0.7mm, Sweep for 1 min.
  - · Dimension and times : X, Y and Z directions for 0.5 hours each.

### (5) Test Method

Fix the D.U.T. on the fitting-stage

## (6) Test Results

PASS

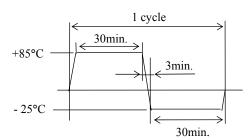
Check item	Spec.		Before Test	After Test
Attenuation (dB)	Differential Mode : 25dBmin.	0.2 MHz	75.15	75.10
		30 MHz	56.05	56.05
		0.1 MHz	32.80	32.80
	Common Mode : 25dBmin.	10 MHz	38.70	38.20
Leakage Current (mA)	5mA max.(500V, 60Hz)	Line1	2.68	2.67
		Line2	2.68	2.67
		Line3	2.69	2.68
DC Resistance (mΩ)	$6 \text{m} \Omega \text{max}.$		2.54	2.54
Test Voltage	L-L : 2192Vdc 60s.		ОК	ОК
	L-E : 2500Vac 60s.		UK	UK
Isolation Resistance (M $\Omega$ )	100M Ω min. (500Vdc 60s)		$1.0 \ge 10^7$	$1.0 \ge 10^7$

#### Typical Sample Data

3. Heat Cycle Test

## MODEL : RTHB-5080 (Representation Product : RTHN-5150)

- (1) Equipment Used TEMPERATURE CHAMBER TSA-71H-W (ESPEC CORP.)
- (2) The Number of D.U.T. (Device Under Test) 2 units
- (3) Test Conditions
  - Ambient Temperature : -25~+85°C
    Test Cycles : 100cycles



(4) Test Method

Before the test check if there is no abnormal characteristics and put the D.U.T. in the testing chamber. Then test it in the above cycles, After the test is completed leave it for 1 hour at room temperature and check it if there is no abnormal each characteristics.

(5) Test Results

PASS

Check item	Spec.		Before Test	After Test
Attenuation (dB)	Differential Mode : 25dBmin.	0.2 MHz	68.95	73.65
		30 MHz	57.70	54.75
		0.1 MHz	33.50	31.50
	Common Mode : 25dBmin.	10 MHz	40.25	40.40
Leakage Current (mA)	5mA max.(500V, 60Hz)	Line1	2.69	2.63
		Line2	2.67	2.65
		Line3	2.67	2.65
DC Resistance (m $\Omega$ )	$6 \text{m} \Omega \text{max}.$		2.47	2.44
Test Voltage	L-L : 2192Vdc 60s.		ОК	ОК
	L-E : 2500Vac 60s.		UK	UK
Isolation Resistance (M $\Omega$ )	100M Ω min. (500Vdc 60s)		$1.0 \ge 10^7$	$1.0 \ge 10^7$

4. Humidity Test

## MODEL : RTHB-5080 (Representation Product : RTHN-5150)

- (1) Equipment Used TEMP. & HUMID. CHAMBER PR-4KT (ESPEC CORP.)
- (2) The Number of D.U.T. (Device Under Test) 2 units

#### (3) Test Conditions

- Ambient Temperature : +40°C
- · Test Time : 500 hours
- Ambient Humidity : 90~95% RH No Dewdrop

### (4) Test Method

Before the test check if there is no abnormal characteristics and put the D.U.T. in the testing chamber. Then test it in the above conditions. After the test is completed leave it for 1 hour at room temperature and check it if there is no abnormal each characteristics.

### (5) Test Results

PASS

Check item	Spec.		Before Test	After Test
Attenuation (dB)	Differential Mode : 25dBmin.	0.2 MHz	71.45	74.75
		30 MHz	54.85	49.00
		0.1 MHz	33.40	33.50
	Common Mode : 25dBmin.	10 MHz	39.15	39.90
Leakage Current (mA)	5mA max.(500V, 60Hz) Line	Line1	2.71	2.66
		Line2	2.70	2.66
		Line3	2.69	2.66
DC Resistance (mΩ)	$6 \text{m} \Omega \text{max}.$		2.51	2.44
Test Voltage	L-L : 2192Vdc 60s.		ОК	ОК
	L-E : 2500Vac 60s.		UK	UK
Isolation Resistance (MΩ)	100M Ω min. (500Vdc 60s)		$1.0 \ge 10^7$	$1.0 \ge 10^7$

#### Typical Sample Data

5. High Temperature Resistance Test

### MODEL : RTHB-5080 (Representation Product : RTHN-5300)

- (1) Equipment Used TEMPERATURE CHAMBER PHH-300 (ESPEC CORP.)
- (2) The Number of D.U.T. (Device Under Test) 2 units
- (3) Test Conditions
  - Ambient Temperature : +50°C
  - Test Time : 500 hours
  - · Operating : DC 300A

## (4) Test Method

Before the test check if there is no abnormal characteristics and put the D.U.T. in the testing chamber. Then test it in the above conditions. After the test is completed leave it for 1 hour at room temperature and check it if there is no abnormal each characteristics.

(5) Test Results

PASS

Check item	Spec.		Before Test	After Test
Attenuation (dB)	Differential Mode : 25dBmin.	0.2 MHz	75.80	78.15
		30 MHz	34.25	38.60
	Common Mode : 25dBmin.	0.5 MHz	34.15	34.40
		6 MHz	38.60	29.55
Leakage Current (mA)	5mA max.(500V, 60Hz)	Line1	2.72	2.65
		Line2	2.72	2.66
		Line3	2.72	2.66
DC Resistance (mΩ)	2m Ω max.		1.02	0.99
Test Voltage	L-L : 2192Vdc 60s.		ОК	ОК
	L-E : 2500Vac 60s.		UK	
Isolation Resistance (M $\Omega$ )	100M Ω min. (500Vdc 60s)		$1.0 \ge 10^7$	$1.0 \ge 10^7$

#### Typical Sample Data

6. Low Temperature Storage Test

### MODEL : RTHB-5080 (Representation Product : RTHN-5150)

- (1) Equipment Used TEMPERATURE CHAMBER PG-2FT (ESPEC CORP.)
- (2) The Number of D.U.T. (Device Under Test) 2 units
- (3) Test Conditions
  - Ambient Temperature : -25°C • Test Time : 500 hours
- (4) Test Method

Before the test check if there is no abnormal characteristics and put the D.U.T. in the testing chamber. Then test it in the above conditions. After the test is completed leave it for 1 hour at room temperature and check it if there is no abnormal each characteristics.

(5) Test Results

PASS

Typical	Sampl	e Data
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Check item	Spec.		Before Test	After Test
Attenuation (dB)	Differential Mode : 25dBmin.	0.2 MHz	69.10	71.70
		30 MHz	54.25	63.80
		0.1 MHz	32.85	32.90
	Common Mode : 25dBmin.	10 MHz	40.20	40.40
Leakage Current (mA)	5mA max.(500V, 60Hz)	Line1	2.73	2.65
		Line2	2.69	2.65
		Line3	2.69	2.65
DC Resistance (mΩ)	$6 \text{m} \Omega \text{max}.$		2.48	2.45
Test Voltage	L-L : 2192Vdc 60s.		ОК	ОК
	L-E : 2500Vac 60s.		UK	UK
Isolation Resistance (M $\Omega$ )	100M Ω min. (500Vdc 60s)		$1.0 \ge 10^7$	$1.0 \ge 10^7$